

Search Notes

Application/Control No.

09/447,052

Examiner

Chau Nguyen

Applicant(s)/Patent under
Reexamination

SUEHIRA, SEISHI

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	513	3/29/2006	CN
715	522	3/29/2006	CN
715	523	3/29/2006	CN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated Search on East Reports	3/29/2006	CN
NPL Search on IEEE Database	3/30/2006	CN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner